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<b>FORM PTO-1449</b> <b>INFORMATION DISCLOSURE STATEMENT</b>				ATTY DOCKET NO. <b>536-009.027</b>		SERIAL NO. To be assigned	
				APPLICANT: <b>Holger RUCKER et al.</b>			
				FILING DATE: <b>Herewith</b>		ART UNIT: To be assigned	
<b>UNITED STATES PATENT DOCUMENTS</b>							
EXAM. INITIAL		DOCUMENT NUMBER	DATE	INVENTOR/ASSIGNEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	US	2002/0117733	Aug. 29, 2002	<i>Michael Farjami, Esq.</i>			
	US	6,642,553	Nov. 4, 2003	<i>Juergen Drews et al.</i>			
	US	2003/0189239	Oct. 9, 2003	<i>Alexander Kalnitsky et al.</i>			
	US	5,523,606	Jun. 4, 1996	<i>Toru Yamazaki</i>			
	US	6,492,238	Dec. 10, 2002	<i>David C. Ahlgren et al.</i>			
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
	EP	0 418 185 A1	Jul. 31, 1990	EP			
	EP	1 128 422 A1	Aug. 29, 2001	EP			
	EP	0 949 665 A2	Apr. 7, 1999	EP			
<b>OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)</b>							
		H.J. Osten et al., <i>The Effect of Carbon Incorporation on SiGe Heterobipolar Transistor Performance and Process Margin</i> ; IEEE 1997 0-7803-4100 (pages 32.4.1 - 32.4.4).					
Examiner (To be assigned)		Date: <span style="float: right;">10/23/2009</span>					

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /L.P./